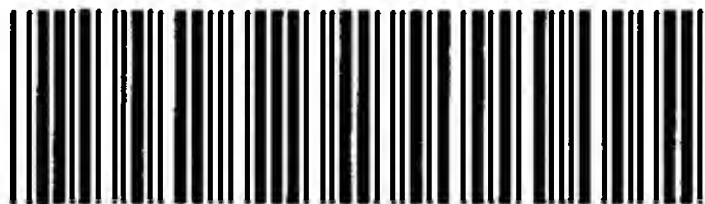


Search Notes



Application/Control No.

10/711,959

Examiner

Phallaka Kik

Applicant(s)/Patent under Reexamination

HENG ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	3,2,9,10	12/26/2006	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB New search Class/sub searched: 716/1-18 (see attached)	12/26/2006	PK
--EPO, JPO, IBM TDB, Derwent new search (see attached)	12/26/2006	PK
IEE/IEEE Xplore new search (see attached)	12/26/2006	PK